11/20/03

10/718400

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	ATTY DOCKET NO. 14846-36	SERIAL NO. TBA
	Methods and Systems For Predicting Software Defects........	
	FILING November 20, 2003	GROUP TBA

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SGN		US 6,073,107	06/06/00	Minkiewicz et al.			
SGN		US 6,477,471	11/05/02	Hedstrom et al.			
SGN		US 6,546,506	04/08/03	Lewis			
SGN		US 5,446,895	08/29/95	White et al.			
SGN		US 5,655,074	08/05/97	Rauscher			
SGN		US 5,758,061	05/26/98	Plum			
SGN		US 5,903,897	05/11/99	Carrier III et al.			
SGN		US 5,960,196	09/28/99	Carrier III et al.			
SGN		US 6,363,524	03/26/02	Loy			
SGN		US 6,405,364	06/11/02	Bowman-Amuah			
SGN		US 6,513,154	01/28/03	Porterfield			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

| SGN | | | Hudepohl, J.P., et al., "Integrating Metrics and Models For Software Risk Assessment," p. 93, The Seventh International Symposium on Software Reliability Engineering (ISSRE'96) October 30-November 02, 1996, White Plains, NY (Abstract) |
| SGN | | | Levendel, Y., "Reliability Analysis of Large Software Systems: Defect Data Modeling," pp. 141-152, IEEE Transactions on Software Engineering (Abstract) |

| EXAMINER /Samuel Neway/ | DATE CONSIDERED 07/21/2006 |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10/718400

INFORMATION DISCLOSURE CITATION *(Use several sheets if necessary)*	**ATTY DOCKET NO.** 14846-36	**SERIAL NO.** ~~TBA~~

ATTY DOCKET NO. 14846-36 **SERIAL NO.** ~~TBA~~

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Methods and Systems For Predicting Software Defects........

FILING November 20, 2003 **GROUP** TBA

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SGN		US 6,519,763	02/11/03	Kaufer et al.			
SGN		US 6,601,017	07/29/03	Kennedy et al.			
SGN		US 6,601,018	07/29/03	Logan			
SGN		US 6,601,233	07/29/03	Underwood			
SGN		US 6,626,953	09/30/03	Johndrew et al.			
SGN		US 6,629,266	09/30/03	Harper et al.			
SGN		US 2002/0147961	10/10/02	Charters et al.			
SGN		US 2002/0162090	10/31/02	Parnell et al.			
SGN		US 2003/0018952	01/23/03	Roetzheim			
SGN		US 2003/0033586	02/13/03	Lawler			
SGN		US 2003/0188290	10/02/03	Corral			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

SGN		Yu, T.J., et al., "An Analysis of Several Software Defect Models," pp. 1261-1270, IEEE Transactions on Software Engineering (Abstract)
SGN		Wohlin, C., et al., "Understanding the Sources of Software Defects: A Filtering Apporach,: 8th International Workshop on Program Comprehension (IWPC'00), June 10-11, 2000 (Abstract)

EXAMINER /Samuel Neway/ **DATE CONSIDERED** 07/21/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION *(Use several sheets if necessary)*	ATTY DOCKET NO. 14846-36	SERIAL NO. 10/718400 ~~TBA~~
	Methods and Systems For Predicting Software Defects........	
	FILING November 20, 2003	GROUP TBA

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SGN		US 2003/0196190	10/16/03	Ruffolo et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

OTHER DOCUMENTS   *(Including Author, Title, Date, Pertinent Pages, Etc.)*

SGN			McConnell, S., "Gauging Software Readiness with Defect Tracking," IEEE Software, pp. 135-136 (Abstract)
SGN			Mohapatra, S., et al., "Defect Prevention through Defect Prediction: A Case Study at Infosys," Utkal University, IEEE International Conference on Softwars Maintenance (ICSM'01), November 7-9, 2001, p. 260 (Abstract)

EXAMINER /Samuel Neway/	DATE CONSIDERED 07/21/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820
(also form PTO-1449)

Copyright 1994-97 LegalStar   P09C/REV03   Patent and Trademark Office * U.S. DEPARTMENT OF COMMERCE

INFORMATION DISCLOSURE CITATION *(Use several sheets if necessary)*	ATTY DOCKET NO. 14846-36	SERIAL NO. 10/718400
	Methods and Systems For Predicting Software Defects........	
	FILING November 20, 2003	GROUP TBA

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

SGN		Basili, V., et al., "Understanding and Prediciting the Process of Software Maintenance Releases," 18th International Conference on Software Engineering (ICSE'96), arch 25-29, 1996, p. 464 (Abstract)
SGN		Fenton, N.E., et al., "A Critique of Software Defect Prediction Models," IEEE Transactions on Software Engineering; pp. 675-689 (Abstract)

EXAMINER /Samuel Neway/	DATE CONSIDERED 07/21/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.